

Notice of References Cited	Application/Control No. 10/707,205	Applicant(s)/Patent Under Reexamination PILEGGI ET AL.	
	Examiner Cynthia Britt	Art Unit 2117	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,815,973 B1	11-2004	Conn, Robert O.	324/765
*	B	US-4,823,136	04-1989	Nathanson et al.	342/368
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09101288 A	04-1997	Japan	SATO et al.	H01L 21/66
	O	JP 2002093675 A	03-2002	Japan	MASUI et al.	H01L 21/02
	P	JP 2004253561 A	09-2004	Japan	MIZUKOSHI, TAKASHI	H01L 21/66
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Testability and Yield of MMICs" by Allen, B.R. This paper appears in: Antennas and Propagation Society International Symposium, 1992 Digest. Held in Conjunction with: URSI Radio Science Meeting and Nuclear EMP Meeting., IEEE Publication Date: 18-25 Jul 1992 On page(s): 1263 vol.3 ISBN: 0-7803-0730-5 INSPEC Accession Number: 4391024
	V	"Measurement Challenges for on-wafer RF-SOC test" by Wai Yuen Lau This paper appears in: 27th Annual IEEE/SEMI International Electronics Manufacturing Technology Symposium, 2002. Publication Date: 2002 On page(s): 353- 359 ISBN: 0-7803-7301-4 INSPEC Accession Number: 7492523
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.